

Notice of References Cited	Application/Control No. 10/726,328	Applicant(s)/Patent Under Reexamination DERDERIAN ET AL.	
	Examiner Matthew W. Such	Art Unit 2891	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2002/0150687	10-2002	Matsuba, Stanley	427/385.5
*	B	US-2003/0224104	12-2003	Fukunaga et al.	427/146
*	C	US-6,207,487	03-2001	Kim et al.	438/238
*	D	US-5,998,824	12-1999	Lee, Young Jong	257/309
*	E	US-2004/0043577	03-2004	Hill, Christopher W.	438/396
*	F	US-2001/0024387	09-2001	Raaijmakers et al.	365/200
*	G	US-6,730,596	05-2004	Fukunaga et al.	438/660
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.